2018년 2월 6일(화), 09:00-10:45
Room G (봉래II+III, 6층)

G. Device & Process Modeling, Simulation and Reliability 분과
[TG1-G] Advanced Devices I - Technology and Simulation
좌장: 김대환 교수(국민대학교), 조인욱 상무(SK 하이닉스)

TG1-G-1 **09:00-09:15**	**AnalysisofCarrier Lifetime Dependence of Dual Gate Positive Feedback Field-Effect Transistorwith Polysilicon Body** Kyungchul Park, Min-Woo Kwon, and Byung-Gook Park *Department of Electrical Engineering, Seoul National University*
TG1-G-2 **09:15-09:30**	**A Study of Radiation Immunity and Damage Recovery in SiGe pMOSF** Ik Kyeong Jin[1], Hagyoul Bae[1], Jun-Young Park[1], Choong-Ki Kim[1], Il-Woong Tcho[1], Seong-Yeon Kim[2], Do-Hyun Kim[2], Yun-Ik Son[2], Jae-Hoon Lee[2], Yong-Taik Kim[2], Seong-Wan Ryu[2], and Yang-Kyu Choi[1] *[1]School of Electrical Engineering, KAIST, [2]SK Hynix Semiconductor Inc*
TG1-G-3 **09:30-09:45**	**Capacitance Matching to Obtain Sub-60mV/Decade Non-hystereticOperation Regime of Negative Capacitance (NC) FET** Pavlo Bidenko[1], Subin Lee[1], Jin Dong Song[1,2], and Sanghyeon Kim[1,2] *[1]KIST, [2]University of Science and Technology*
TG1-G-4 **09:45-10:00**	**Effects of Shell Thickness on Performance of GaSb/InAs Core-Shell Nanowire pMOSFETs** Hyeongu Lee and Mincheol Shin *Department of Electronic Engineering, KAIST*
TG1-G-5 **10:00-10:15**	**Analysis of Performance in Nanosheet FET with Negative Capacitance** Changbeom Woo[1], Jang Kyu Lee[1], Jongsu Kim[1], Myounggon Kang[2], and Hyungcheol Shin[1] *[1]ISRC and School of Electrical Engineering and Computer Science, Seoul National University, [2]Department of Electronics Engineering, Korea National University of Transportation*
TG1-G-6 **10:15-10:30**	**Statistical Analysis of NBTI Considering Trap Position in Nanosheet FET** Shinkeun Kim[1], Dokyun Son[1], Kyul Ko[1], Myounggon Kang[2], and Hyungcheol Shin[1] *[1]ISRC and School of Electrical Engineering and Computer Science, Seoul National University, [2]Department of Electronics Engineering, Korea National University of Transportation*
TG1-G-7 **10:30-10:45**	**Si-Ge Hetero PN TFET with Junctionless Nanowire FET** Ju-Chan Lee, Tae Jun Ahn, and Yun Seop Yu *Department of Electrical, Electronic and Control Engineering and IITC, Hankyong National University*